# 74F38

# Quad 2-input NAND buffer (open collector) Rev. 3 — 10 January 2014

Product data sheet

#### **General description** 1.

The 74F38 provides four 2-input NAND functions with open-collector outputs.

#### 2. **Features and benefits**

■ Industrial temperature range available (-40 °C to +85 °C)

#### **Ordering information** 3.

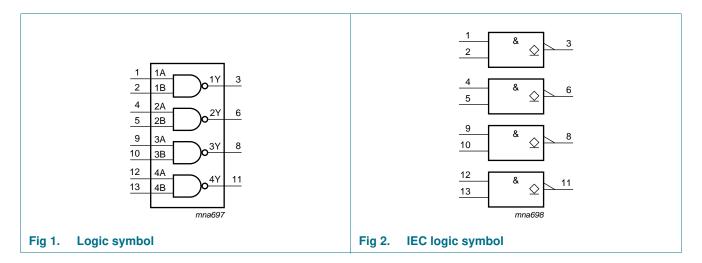
#### Table 1. **Ordering information**

Type number	Package							
	Temperature range	Name	Description	Version				
N74F38N	0 °C to +70 °C	DIP14	DIP14 plastic dual in-line package; 14 leads (300 mil)					
174F38N	$-40~^{\circ}\text{C}$ to +85 $^{\circ}\text{C}$							
N74F38D	0 °C to +70 °C	SO14	SO14 plastic small outline package; 14 leads; body width					
174F38D	–40 °C to +85 °C	_	3.9 mm					



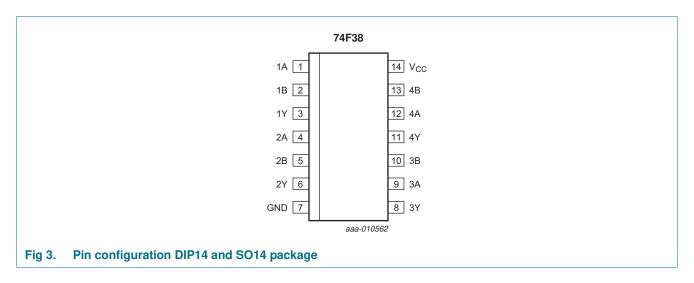
**Quad 2-input NAND buffer (open collector)** 

# 4. Functional diagram



# 5. Pinning information

## 5.1 Pinning



### **Quad 2-input NAND buffer (open collector)**

## 5.2 Pin description

Table 2. Pin description

Symbol	Pin	Description	Unit load HIGH/LOW	Load value[1][2] HIGH/LOW
1A, 2A, 3A, 4A	1, 4, 9, 12	data input	1.0/2.0	20 μA/1.2 mA
1B, 2B, 3B, 4B	2, 5, 10, 13	data input	1.0/2.0	20 μA/1.2 mA
1Y, 2Y, 3Y, 4Y	3, 6, 8, 11	data output	OC/106.7	OC/64 mA
GND	7	ground (0 V)	-	-
V <sub>CC</sub>	14	supply voltage	-	-

<sup>[1]</sup> One FAST Unit Load (UL) is defined as 20  $\mu A$  in HIGH state, 0.6 mA in LOW state.

## 6. Functional description

Table 3. Function table[1]

Input		Output
nA	nB	nY
L	L	Н
L	Н	Н
Н	L	Н
Н	Н	L

<sup>[1]</sup> H = HIGH voltage level; L = LOW voltage level; X = don't care; Z = high-impedance OFF-state.

# 7. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{CC}$	supply voltage		-0.5	+7.0	V
VI	input voltage		<u>[1]</u> –0.5	+7.0	V
Vo	output voltage	output in HIGH-state	<u>[1]</u> –0.5	$V_{CC}$	V
I <sub>IK</sub>	input clamping current	$V_I < 0 V$	-30	+5	mA
Io	output current	output in LOW-state	-	128	mA
T <sub>amb</sub>	ambient temperature	in free-air	[2]		
		commercial	0	70	°C
		industrial	-40	+85	°C
T <sub>stg</sub>	storage temperature		-65	+150	°C

<sup>[1]</sup> The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

<sup>[2]</sup> OC = open collector.

<sup>[2]</sup> The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability. The maximum junction temperature of this integrated circuit should not exceed 150 °C.

## **Quad 2-input NAND buffer (open collector)**

# 8. Recommended operating conditions

Table 5. Recommended operating conditions

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$V_{CC}$	supply voltage		4.5	5.0	5.5	V
$V_{IH}$	HIGH-level input voltage		2.0	-	-	V
$V_{IL}$	LOW-level input voltage		-	-	0.8	V
$V_{OH}$	HIGH-level output voltage		-	-	4.5	V
I <sub>IK</sub>	input clamping current		-18	-	-	mA
I <sub>OL</sub>	LOW-level output current		-	-	64	mA

## 9. Static characteristics

Table 6. Static characteristics

Symbol	Parameter	Conditions		25 °C			+70 °C	Unit
			Min	Typ[1]	Max	Min	Max	
$V_{IK}$	input clamping voltage	$V_{CC} = 4.5 \text{ V}; I_{IK} = -18 \text{ mA}$	-1.2	-0.73	-	-1.2	-	٧
$V_{OL}$	LOW-level output	$V_{CC} = 4.5 \text{ V}; V_{IL} = 0.8 \text{ V}; V_{IH} = 2.0 \text{ V}$						
	voltage	I <sub>OL</sub> = 64 mA						
		V <sub>CC</sub> = ±10 %	-	-	-	-	0.55	V
		V <sub>CC</sub> = ±5 %	-	0.42	-	-	0.55	V
I	input leakage current	$V_{CC} = 0 \ V; \ V_I = 7.0 \ V$	-	-	-	-	100	μΑ
I <sub>IH</sub>	HIGH-level input current	$V_{CC} = 5.5 \text{ V}; V_I = 2.7 \text{ V}$	-	-	-	-	20	μΑ
I <sub>IL</sub>	LOW-level input current	$V_{CC} = 5.5 \text{ V}; V_I = 0.5 \text{ V}$	-	-	-	-20	-	μΑ
I <sub>CC</sub> supply current	supply current	V <sub>CC</sub> = 5.5 V						
		$V_I = GND$	-	4	-	-	7	mΑ
		V <sub>I</sub> = 4.5 V	-	22	-	-	30	mA

<sup>[1]</sup> All typical values are measured at  $V_{CC} = 5 \text{ V}$ .

# 10. Dynamic characteristics

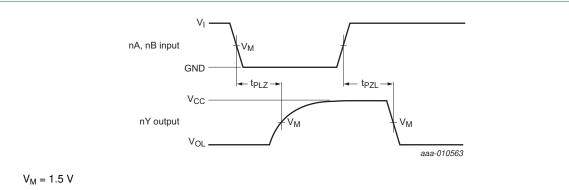
 Table 7.
 Dynamic characteristics

GND = 0 V. Test circuit is shown in Figure 6.

Symbol	Parameter	Conditions	,		0 °C to +70 °C; V <sub>CC</sub> = 5.0 V ± 0.5 V		-40 °C to +85 °C; V <sub>CC</sub> = 5.0 V ± 0.5 V		Unit	
			Min	Тур	Max	Min	Max	Min	Max	
t <sub>PZL</sub>	OFF-state to LOW propagation delay	nA, nB to nY; see Figure 4	1.5	3.0	5.0	1.5	5.5	1.5	6.0	ns
t <sub>PLZ</sub>	LOW to OFF-state propagation delay	nA, nB to nY; see <u>Figure 4</u>	7.5	10.0	12.5	7.5	13.0	7.5	14.5	ns

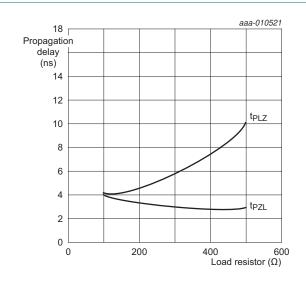
### **Quad 2-input NAND buffer (open collector)**

## 11. Waveforms



VOL is a typical output voltage level that occurs with the output load.

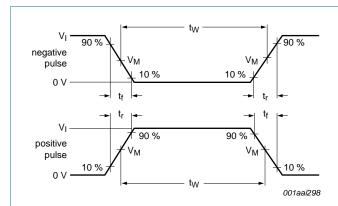
Fig 4. Propagation delay for inverting outputs

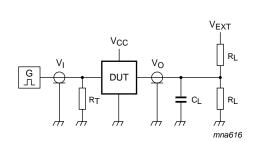


When using open collector parts, the value of the pull-up resistor greatly affects the value of the  $t_{PLZ}$ . For example, changing the specified pull-up resistor value from 500  $\Omega$  to 100  $\Omega$  improves the  $t_{PLZ}$  up to 50% with only a slight increase in the  $t_{PZL}$ . However, if the value of the pull-up resistor is changed, the user must ensure that the total  $t_{OL}$  current through the resistor and the total  $t_{IL}$  of the receivers, does not exceed the  $t_{IL}$  minimum specification.

Fig 5. Typical propagation delays versus load for open collector outputs

## **Quad 2-input NAND buffer (open collector)**





b. Test circuit

a. Input pulse definition

Test data is given in Table 8.

Test circuit definitions:

 $R_L$  = Load resistance.

 $C_L$  = Load capacitance including jig and probe capacitance.

 $R_T$  = Termination resistance should be equal to output impedance  $Z_0$  of the pulse generator.

 $V_{EXT}$  = Test voltage for switching times.

Fig 6. Load circuitry for switching times

Table 8. Test data

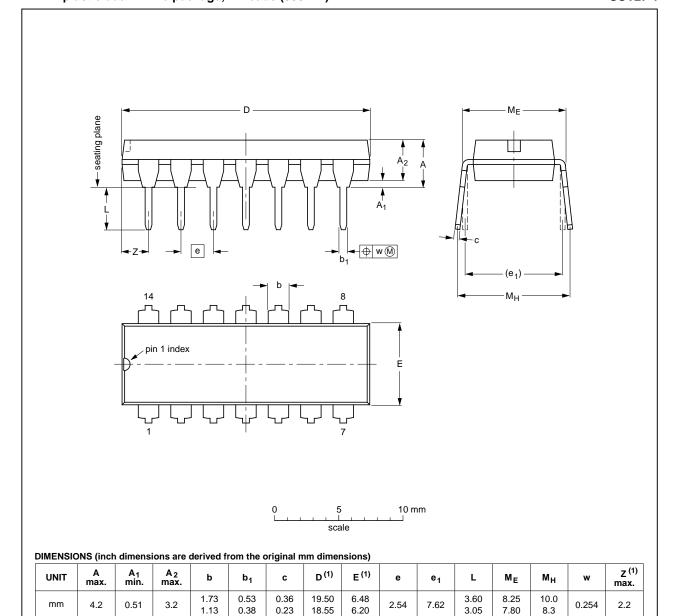
Input			Load		V <sub>EXT</sub>	
VI	f <sub>i</sub>	t <sub>W</sub>	t <sub>r</sub> , t <sub>f</sub>	CL	R <sub>L</sub>	t <sub>PZL</sub> , t <sub>PLZ</sub>
3.0 V	1 MHz	500 ns	≤ 2.5 ns	50 pF	500 Ω	7.0 V

## **Quad 2-input NAND buffer (open collector)**

## 12. Package outline

## DIP14: plastic dual in-line package; 14 leads (300 mil)

SOT27-1



#### Note

inches

0.17

0.068

0.044

0.021

0.015

0.014

0.009

0.77

0.14

0.32

0.39

0.01

0.087

OUTLINE		REFER	ENCES	EUROPEAN	ISSUE DATE
VERSION	IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE
SOT27-1	050G04	MO-001	SC-501-14		<del>99-12-27</del> 03-02-13

0.1

0.3

Fig 7. Package outline SOT27-1 (DIP14)

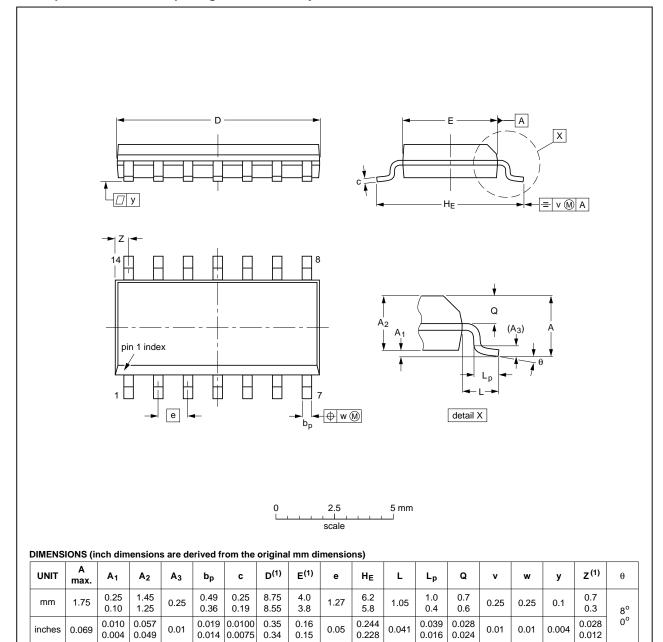
0.02

0.13

<sup>1.</sup> Plastic or metal protrusions of 0.25 mm (0.01 inch) maximum per side are not included.

SO14: plastic small outline package; 14 leads; body width 3.9 mm

SOT108-1



#### Note

1. Plastic or metal protrusions of 0.15 mm (0.006 inch) maximum per side are not included.

OUTLINE		REFER	ENCES	EUROPEAN	ISSUE DATE
VERSION	IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE
SOT108-1	076E06	MS-012			<del>99-12-27</del> 03-02-19

Fig 8. Package outline SOT108-1 (SO14)

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## **Quad 2-input NAND buffer (open collector)**

## 13. Abbreviations

#### Table 9. Abbreviations

Acronym	Description
CDM	Charged-Device Model
CMOS	Complementary Metal Oxide Semiconductor
DUT	Device Under Test
ESD	ElectroStatic Discharge
НВМ	Human Body Model
MM	Machine Model
TTL	Transistor-Transistor Logic

# 14. Revision history

## Table 10. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes		
74F38 v.3	20140110	Product data sheet	-	74F38 v.2		
Modifications:	Modifications:  • The format of this data sheet has been redesigned to comply with the new identity guidelines of NXP Semiconductors.					
	<ul> <li>Legal texts</li> </ul>	have been adapted to the i	new company name whe	re appropriate.		
	<ul> <li>General up</li> </ul>	date of values				
74F38 v.2	19901004	Product specification	-	-		

#### **Quad 2-input NAND buffer (open collector)**

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Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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